



TEST REPORT

Reference No..... : WTX21X10115159E
 Applicant : Acrox Technologies Co, Ltd.
 Address : 4F, No.89, Minshan St, Neihu Dist,Taipei City 114, Taiwan
 Product : Gaming Mouse
 Test Model : GM200*****(*=A~Z,a~z,0~9,/ ,or blank),JGH
 Standards : EN 55032:2015+A11:2020
 : EN 55035:2017+A11:2020
 Date of Receipt sample : Jun. 23, 2020
 Date of Test..... : Jun. 23, 2020 to Jun. 29, 2020
 Date of Issue : Oct. 28, 2021
 Test Result..... : Pass

Remarks:

The results shown in this test report refer only to the sample(s) tested, this test report cannot be reproduced, except in full, without prior written permission of the company. The report would be invalid without specific stamp of test institute and the signatures of compiler and approver.

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Revision History

Report No.	Version	Description	Issue Date	Note
WTX20X06039550E	Original	Initial report	2020-06-29	Invlid
WTX21X10115159E	Re.1	1. Update to the latest standards	2021-10-28	Valid

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1. GENERAL INFORMATION

1.1 Product Description for Equipment Under Test (EUT)

Client Information

Applicant: Acrox Technologies Co, Ltd.
 Address of applicant: 4F, No.89, Minshan St, Neihu Dist, Taipei City 114, Taiwan

Manufacturer: TPV Electronics (Fujian) Co, Ltd.
 Address of manufacturer: Rongqiao Economic and Technological Development Zone, Fuqing City, Fujian Province, P.R.China

General Description of EUT	
Product Name:	Gaming Mouse
Trade Name:	TPV
Model No.:	GM200*****(*=A~Z,a~z,0~9,/ ,or blank)
Adding Model(s):	JGH
<p><i>Note: The test data is gathered from a production sample, provided by the manufacturer. The appearance of others models listed in the report is different from main-test model GM200*****, but the circuit and the electronic construction do not change, declared by the manufacturer.</i></p>	

Technical Characteristics of EUT	
Rated Voltage:	DC 5V
Rated Current:	/
Rated Power:	/
Power Adaptor Model:	/
Highest Internal Frequency:	Below 108MHz
Classification of Equipment:	Class B



1.2 Test Standards

The tests were performed according to following standards:

EN 55032:2015+A11:2020: Electromagnetic compatibility of multimedia equipment - Emission requirements.

EN 55035:2017+A11:2020: Electromagnetic compatibility of multimedia equipment - Immunity requirements.

Maintenance of compliance is the responsibility of the manufacturer. Any modification of the product maybe which result in lowering the emission/immunity should be checked to ensure compliance has been maintained.

1.3 Test Methodology

All measurements contained in this report were conducted with the standards EN 55032 and EN 55035 for electromagnetic compatibility of multimedia equipment, and all related testing and measurement techniques intentional standards.

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1.4 EUT Setup and Operation Mode

The equipment under test (EUT) was configured to measure its highest possible emission/immunity level. The test modes were adapted according to the operation manual for use, more detailed description as follows:

Test Mode List			
Test Mode	Description	Remark	Power Supply Mode
TM1	Linked notebook work	USB Port (DC 5V)	Notebook power supply(DC 5V)

EUT Cable List and Details			
Cable Description	Length (m)	Shielded/Unshielded	With / Without Ferrite
DC cable	1.7	Shielded	With Core

Special Cable List and Details			
Cable Description	Length (m)	Shielded/Unshielded	With / Without Ferrite
/	/	/	/

Auxiliary Equipment List and Details			
Description	Manufacturer	Model	Serial Number
Laptop computer	lenovo	310-14ISK	/

1.5 Performance Criteria for EMS

All the test data has been collected, reduced, and analyzed within this report in accordance with Immunity requires the following as specific performance criteria:

- A. The apparatus shall continue to operate as intended during and after the test. The manufacturer specifies some minimum performance level. The performance level may be specified by the manufacturer as a permissible loss of performance.
- B. The apparatus shall continue to operate as intended after the test. This indicates that the EUT does not need to function at normal performance levels during the test, but must recover. Again some minimal performance is defined by the manufacturer. No change in operating state or loss of data is permitted.
- C. Temporary loss of function is allowed. Operation of the EUT may stop as long as it is either automatically reset or can be manually restored by operation of the controls.



1.6 Test Equipment List and Details

Description	Manufacturer	Model	Serial No.	Cal. Date	Due. Date
Spectrum Analyzer	Rohde & Schwarz	FSP	836079/035	2020-04-28	2021-04-27
EMI Test Receiver	Rohde & Schwarz	ESVB	825471/005	2020-04-28	2021-04-27
Amplifier	Agilent	8447F	3113A06717	2020-04-28	2021-04-27
Amplifier	C&D	PAP-1G18	2002	2020-04-28	2021-04-27
Trilog Broadband Antenna	Schwarz beck	VULB9163	9163-333	2019-05-05	2021-05-04
Trilog Broadband Antenna	Schwarz beck	VULB9163(B)	9163-635	2019-05-05	2021-05-04
Horn Antenna	ETS	3117	00086197	2019-05-05	2021-05-04
EMI Test Receiver	Rohde & Schwarz	ESPI	101611	2020-04-28	2021-04-27
EMI Test Receiver	Rohde & Schwarz	ESPI	101391	2020-04-28	2021-04-27
Pulse Limiter	Rohde & Schwarz	ESH3-Z2	100911	2020-04-28	2021-04-27
AC LISN	Schwarz beck	NSLK8126	8126-224	2020-04-28	2021-04-27
8-WIRE LISN	Schwarz beck	8158	CAT3-8158-0059	2020-04-28	2021-04-27
8-WIRE LISN	Schwarz beck	8158	CAT5-8158-0117	2020-04-28	2021-04-27
PMF Generator	LIONCEL	PMF-801C-C	0171101	2020-04-28	2021-04-27
PMF Antenna	LIONCEL	PMF-801C-A	0180302	2020-04-28	2021-04-27
Instantaneous PMF Generator Module	LIONCEL	PMF-801C-T	0171001	2020-04-28	2021-04-27
Digital Power Analyzer	California Instrument	CTS	72831	2020-04-28	2021-04-27
Power Source	California Instrument	5001IX-CTS-400	25965	2020-04-28	2021-04-27
ESD Generator	LIONCEL	ESD-203B	0170901	2020-04-28	2021-04-27
Amplifier	Agilent	8447D	2944A10179	2020-04-28	2021-04-27
Transient 2000	EMC PARTNER	TRA2000	863	2020-04-28	2021-04-27
Couple Clamp	EMC PARTNER	CN-EFT1000	513	2020-04-28	2021-04-27
CONDUCTED IMMUNITY TEST SYSTEM	FRANKONIA	CIT-10/75	126B1247/2013	2020-01-13	2021-01-12
Attenuator	EMTEST	MA-5100/6BF2	1009	2020-04-28	2021-04-27
CDN	Luthi	L-801M2/M3	2665	2020-04-28	2021-04-27
EM Injection Clamp	FCC	F-203I-23mm	91536	2020-05-28	2021-05-27
Signal Generator	HP	8688B	3438A00604	2020-04-28	2021-04-27
Power Meter	KEITHLEY	3500	1162591	2020-04-28	2021-04-27
Power Meter	KEITHLEY	3500	1121428	2020-04-28	2021-04-27
RF Power Amplifier	MicoTop	MPA-80-1000-250	MPA1906239	2020-04-28	2021-04-27
RF Power Amplifier	MicoTop	MPA-80-1000-100	MPA1906238	2020-04-28	2021-04-27
Antenna	SCHWARZBECK	STLP 9129	9129 114	N/A	N/A



2. SUMMARY OF TEST RESULTS

Standards	Description of Test Item	Result
EN 55032	Conducted Emission	Compliant
	Radiated Emission	Compliant
EN 61000-3-2	Harmonic Current Emission	N/A
EN 61000-3-3	Voltage Fluctuation and Flicker	N/A
EN 55035	Electrostatic Discharge Immunity in accordance with EN 61000-4-2	Compliant
	Continuous RF electromagnetic field Disturbances Immunity in accordance with EN 61000-4-3	Compliant
	Electrical Fast Transient/Burst Immunity in accordance with EN 61000-4-4	Compliant
	Surges Immunity in accordance with EN 61000-4-5	Compliant
	Continuous induced RF disturbances Immunity in accordance with EN 61000-4-6	Compliant
	Power-frequency Magnetic Fields Immunity in accordance With EN 61000-4-8	Compliant
	Voltage Dips/Interruptions Immunity in accordance with EN 61000-4-11	N/A
	Broadband impulse noise disturbances, repetitive	N/A
Broadband impulse noise disturbances, isolated	N/A	

N/A: not applicable



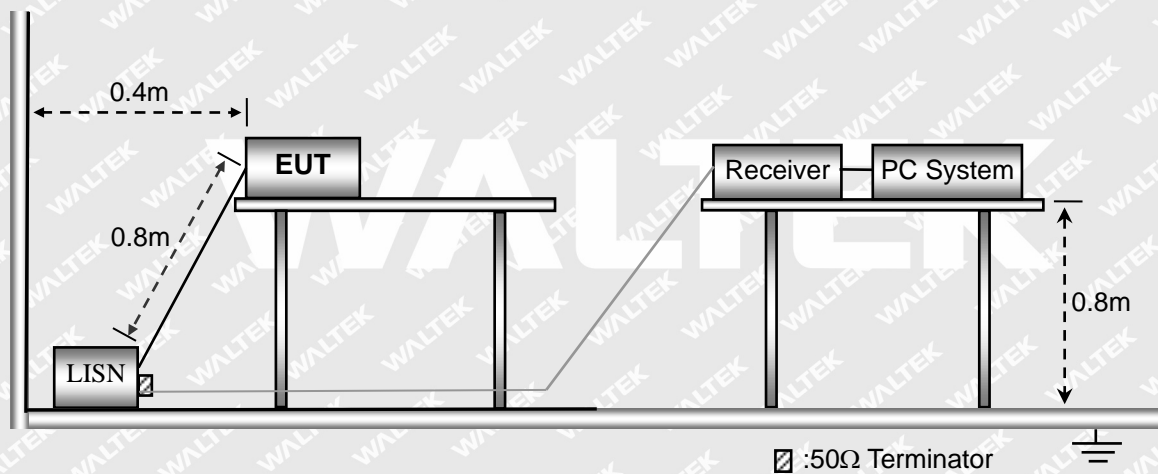
3. Conducted Emission

3.1 Measurement Uncertainty

Base on NIS 81, The Treatment of Uncertainty in EMC Measurements, the best estimate of the uncertainty of any conducted emissions measurement:

Measurement uncertainty		
Parameter	Conditions	Uncertainty
Conducted Emissions	Conducted	9-150kHz $\pm 3.74\text{dB}$
		0.15-30MHz $\pm 3.34\text{dB}$

3.2 Basic Test Setup Block Diagram





3.3 Environmental Conditions

Temperature:	22 ° C
Relative Humidity:	55 %
ATM Pressure:	1015 mbar

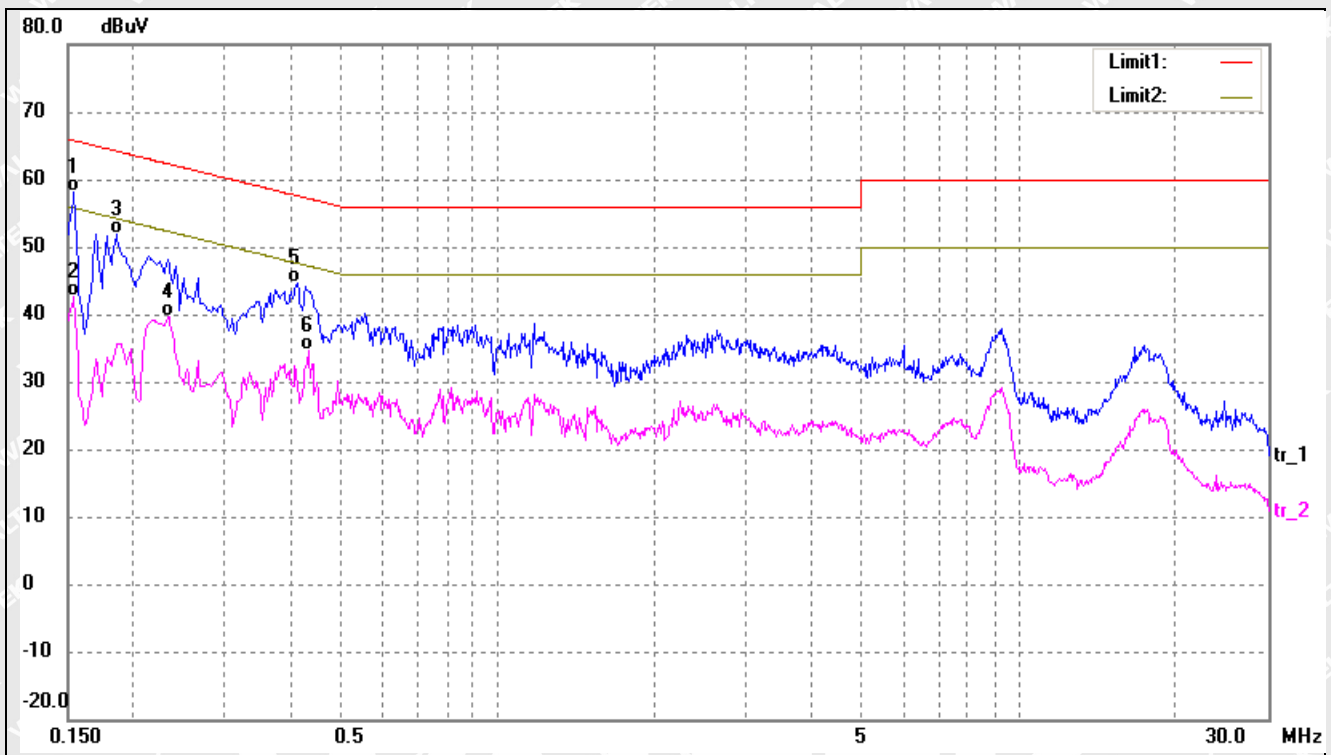
3.4 Summary of Test Results

Look at the graphs and data below:

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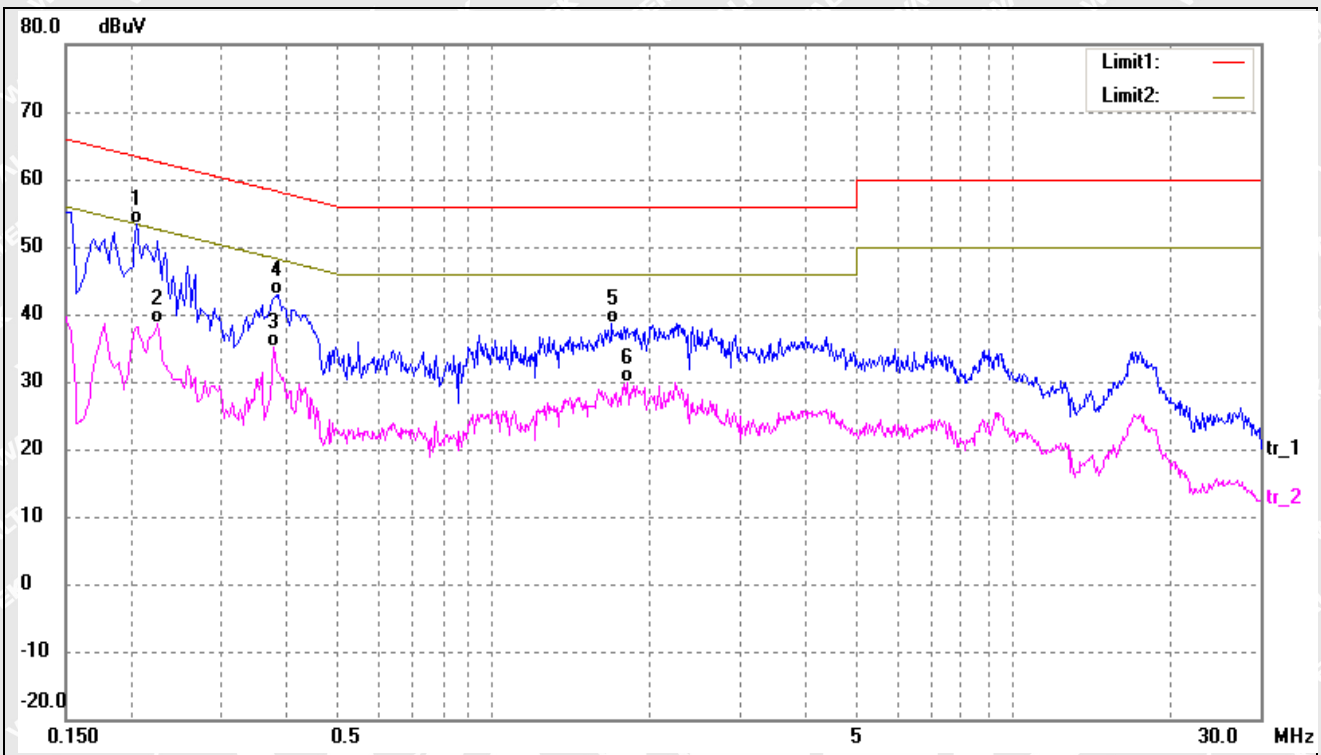
Test mode:	TM1	Polarity:	Line
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No.	Frequency (MHz)	Reading (dBuV)	Correct (dB/m)	Result (dBuV)	Limit (dBuV)	Margin (dB)	Detector
1*	0.1540	48.19	9.95	58.14	65.78	-7.64	QP
2	0.1540	32.71	9.95	42.66	55.78	-13.12	AVG
3	0.1860	41.85	9.96	51.81	64.21	-12.40	QP
4	0.2340	29.63	10.00	39.63	52.31	-12.68	AVG
5	0.4140	34.70	10.01	44.71	57.57	-12.86	QP
6	0.4340	24.64	10.01	34.65	47.18	-12.53	AVG



Test mode:	TM1	Polarity:	Neutral
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No.	Frequency (MHz)	Reading (dBuV)	Correct (dB/m)	Result (dBuV)	Limit (dBuV)	Margin (dB)	Detector
1*	0.2060	43.34	9.97	53.31	63.36	-10.05	QP
2	0.2260	28.63	9.99	38.62	52.59	-13.97	AVG
3	0.3780	25.11	10.02	35.13	48.32	-13.19	AVG
4	0.3860	32.90	10.02	42.92	58.15	-15.23	QP
5	1.6940	28.15	10.37	38.52	56.00	-17.48	QP
6	1.8140	19.46	10.37	29.83	46.00	-16.17	AVG



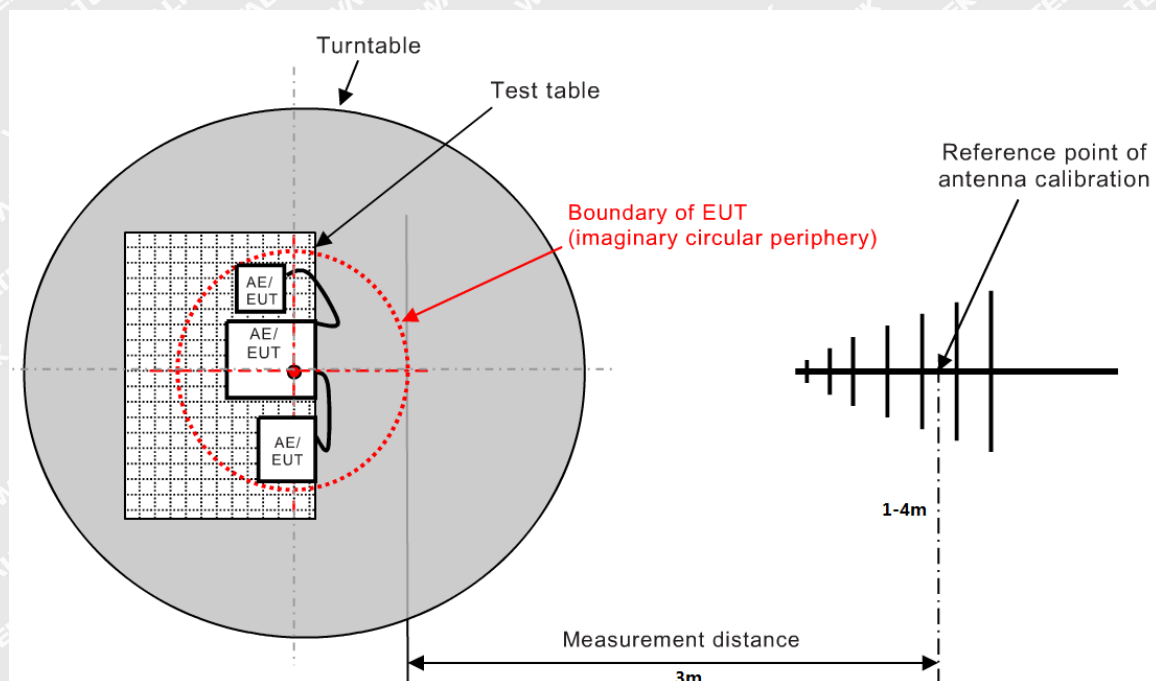
4. Radiated Emission

4.1 Measurement Uncertainty

Base on NIS 81, The Treatment of Uncertainty in EMC Measurements, the best estimate of the uncertainty of any radiation emissions measurement:

Measurement uncertainty		
Parameter	Conditions	Uncertainty
Radiated Emissions	Radiated	30-200MHz $\pm 4.52\text{dB}$
		0.2-1GHz $\pm 5.56\text{dB}$
		1-6GHz $\pm 3.84\text{dB}$
		6-18GHz $\pm 3.92\text{dB}$

4.2 Basic Test Setup Block Diagram





4.3 Corrected Amplitude & Margin Calculation

The Corrected Amplitude is calculated by adding the Antenna Factor and the Cable Factor, and subtracting the Amplifier Gain from the Amplitude reading. The basic equation is as follows:

$$\text{Corr. Ampl.} = \text{Indicated Reading} + \text{Correct Correct} = \text{Ant. Factor} + \text{Cable Loss} - \text{Ampl. Gain}$$

The “**Margin**” column of the following data tables indicates the degree of compliance with the applicable limit. For example, a margin of $-6\text{dB}\mu\text{V}$ means the emission is $6\text{dB}\mu\text{V}$ below the maximum limit for Class B device. The equation for margin calculation is as follows:

$$\text{Margin} = \text{Corr. Ampl.} - \text{EN 55032 Class B Limit}$$

4.4 Environmental Conditions

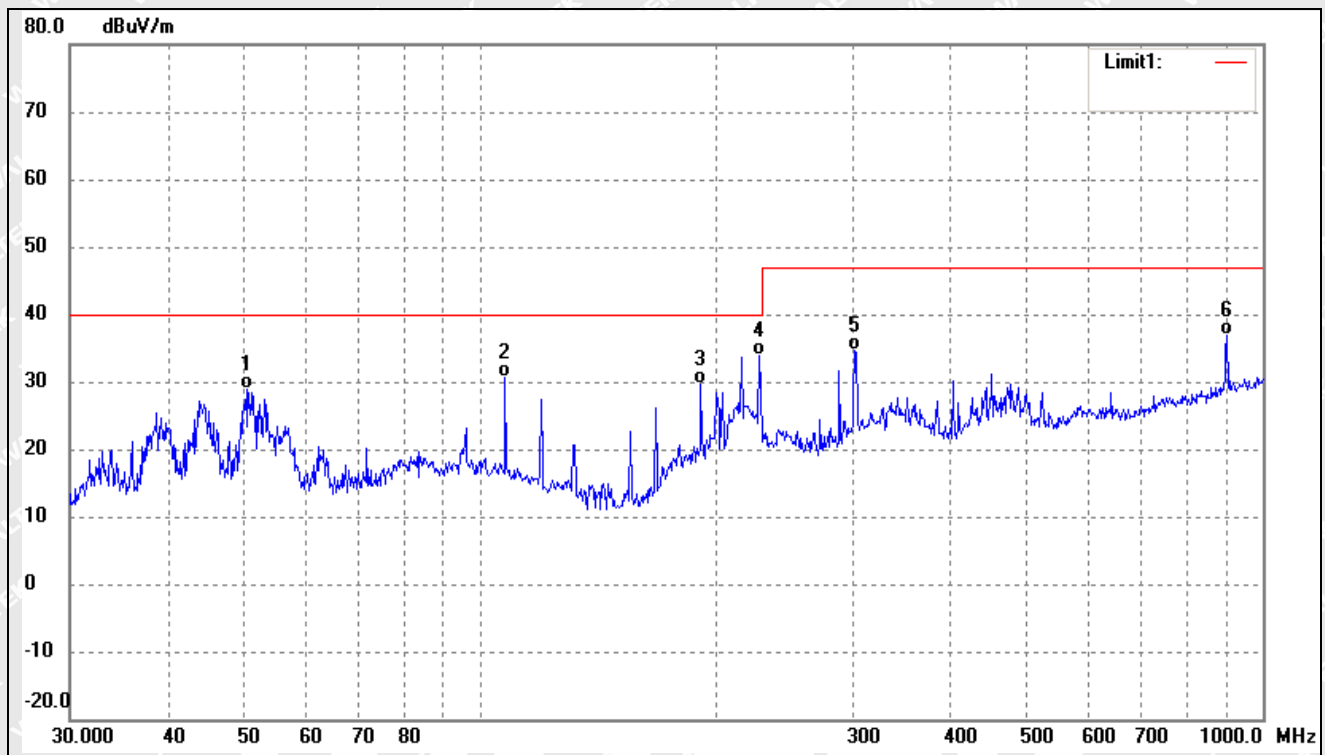
Temperature:	23° C
Relative Humidity:	53%
ATM Pressure:	1011 mbar

4.5 Summary of Test Results

Look at the graphs and data below:



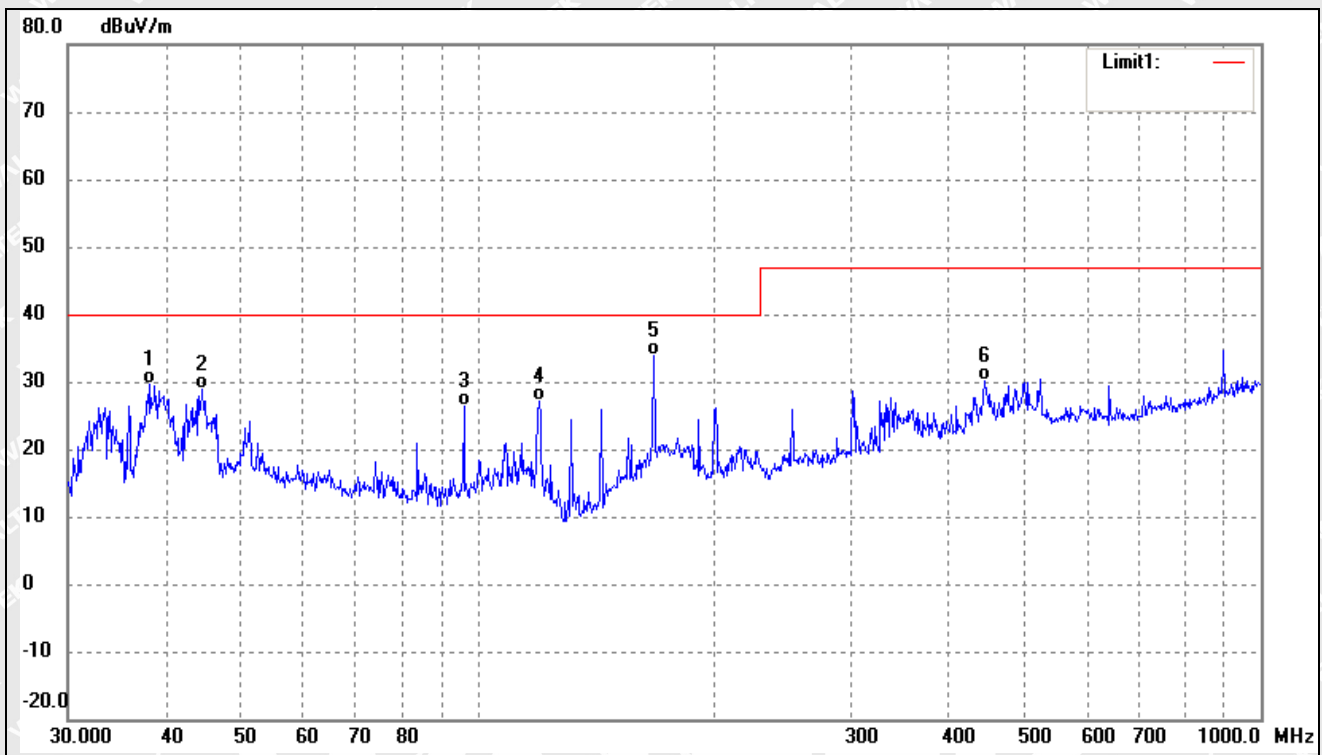
Test mode:	TM1	Polarity:	Horizontal
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No.	Frequency (MHz)	Reading (dBuV/m)	Correct dB/m	Result (dBuV/m)	Limit (dBuV/m)	Margin (dB)	Degree (°)	Height (cm)	Remark
1	50.4089	39.13	-10.28	28.85	40.00	-11.15	281	100	QP
2	107.8877	42.93	-12.20	30.73	40.00	-9.27	92	100	QP
3	191.7450	41.49	-11.93	29.56	40.00	-10.44	331	100	QP
4	227.6906	44.55	-10.60	33.95	40.00	-6.05	97	100	QP
5	301.4224	41.75	-7.24	34.51	47.00	-12.49	217	100	QP
6	900.1474	35.22	1.58	36.80	47.00	-10.20	115	100	QP



Test mode:	TM1	Polarity:	Vertical
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No.	Frequency (MHz)	Reading (dBuV/m)	Correct (dB/m)	Result (dBuV/m)	Limit (dBuV/m)	Margin (dB)	Degree (°)	Height (cm)	Remark
1	38.2120	41.63	-12.07	29.56	40.00	-10.44	149	100	QP
2	44.5868	39.42	-10.66	28.76	40.00	-11.24	114	100	QP
3	96.0986	39.54	-13.17	26.37	40.00	-13.63	97	100	QP
4	119.8556	40.23	-13.21	27.02	40.00	-12.98	132	100	QP
5	167.8243	47.65	-13.81	33.84	40.00	-6.16	184	100	QP
6	443.2943	34.69	-4.46	30.23	47.00	-16.77	308	100	QP



5. Electrostatic Discharges (ESD)

5.1 Test Procedure

Test is conducting under the description of EN 61000-4-2.

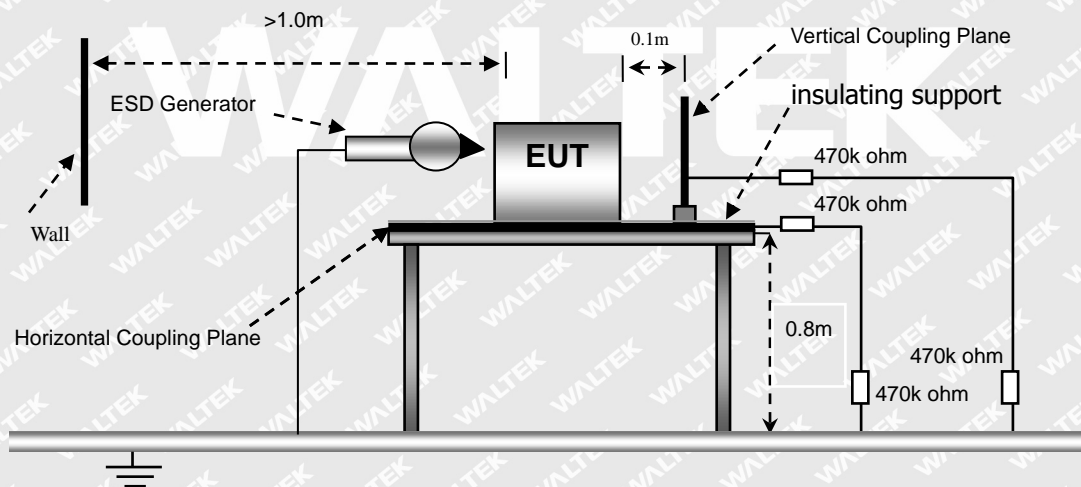
5.2 Test Performance

Performance Criterion: B

5.3 Environmental Conditions

Temperature:	26 °C
Relative Humidity:	55%
ATM Pressure:	1011 mbar

5.4 Basic Test Setup Block Diagram





5.5 Electrostatic Discharge Immunity Test Data

Table 1: Electrostatic Discharge Immunity (Air Discharge)

EN 61000-4-2	Test Voltage (kV)									
Test Points	-2	+2	-4	+4	-6	+6	-8	+8	-15	+15
Surface crack	/	/	/	/	/	/	A	A	/	/

Table 2: Electrostatic Discharge Immunity (Direct Contact)

EN 61000-4-2	Test Voltage (kV)									
Test Points	-2	+2	-4	+4	-6	+6	-8	+8	-15	+15
screw	/	/	A	A	/	/	/	/	/	/

Table 3: Electrostatic Discharge Immunity (Indirect Contact HCP & VCP)

EN 61000-4-2	Test Voltage (kV)									
Test Points	-2	+2	-4	+4	-6	+6	-8	+8	-15	+15
HCP (6 Sides)	/	/	A	A	/	/	/	/	/	/
VCP (4 Sides)	/	/	A	A	/	/	/	/	/	/

Test Result: Pass



6. Continuous RF electromagnetic field Disturbances (RS)

6.1 Test Procedure

Test is conducting under the description of EN 61000-4-3.

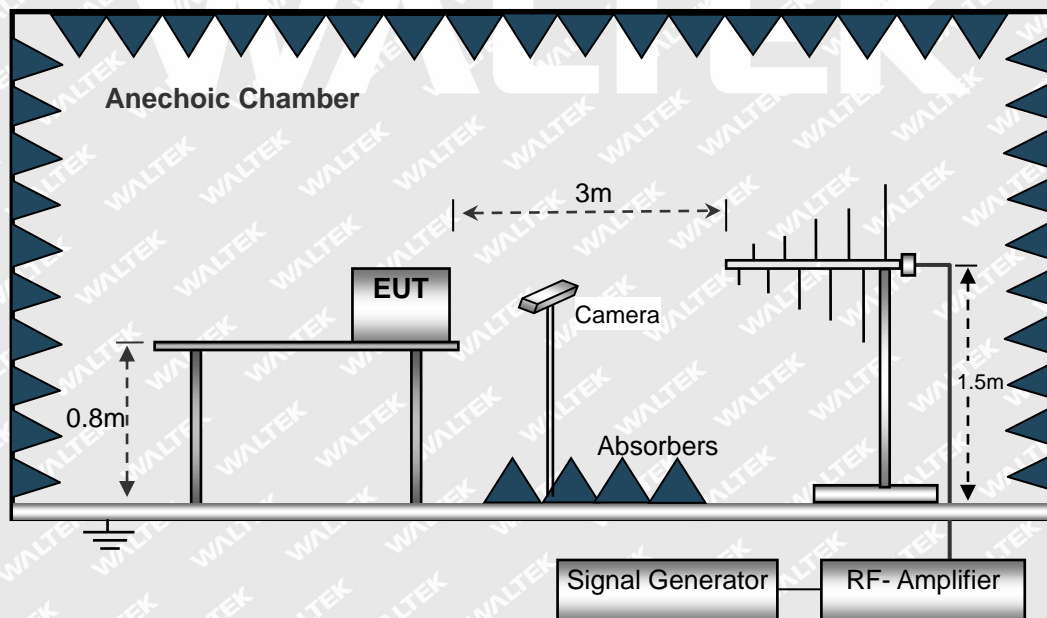
6.2 Test Performance

Performance Criterion: A

6.3 Environmental Conditions

Temperature:	25 °C
Relative Humidity:	52%
ATM Pressure:	1010 mbar

6.4 Basic Test Setup Block Diagram





6.5 Continuous Radiated Disturbances Test Data

Frequency step: 1% of fundamental

Dwell time: 1 second

Modulation: AM by 1kHz sine wave with 80% modulation depth

Frequency Range(MHz)	Field (V/m)	Front		Rear		Left Side		Right Side	
		VERT	HORI	VERT	HORI	VERT	HORI	VERT	HORI
80-1000	3	A	A	A	A	A	A	A	A

Spot frequencies (MHz)	Field (V/m)	Front		Rear		Left Side		Right Side	
		VERT	HORI	VERT	HORI	VERT	HORI	VERT	HORI
1800	3	A	A	A	A	A	A	A	A
2600	3	A	A	A	A	A	A	A	A
3500	3	A	A	A	A	A	A	A	A
5000	3	A	A	A	A	A	A	A	A

Test Result: Pass



7. Electrical Fast Transients (EFT)

7.1 Test Procedure

Test is conducting under the description of EN 61000-4-4.

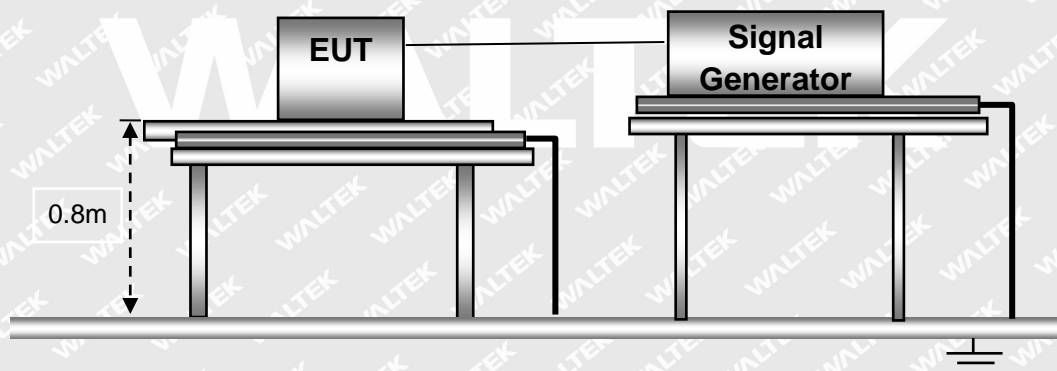
7.2 Test Performance

Performance Criterion: B

7.3 Environmental Conditions

Temperature:	22 °C
Relative Humidity:	53%
ATM Pressure:	1011 mbar

7.4 Basic Test Setup Block Diagram





7.5 Electrical Fast Transients Test Data

EN 61000-4-4 Test Points		Test Voltage (kV)							
		+0.5	-0.5	+1.0	-1.0	+2.0	-2.0	+4.0	-4.0
Power Supply Power Port of EUT	L1	/	/	A	A	/	/	/	/
	L2	/	/	A	A	/	/	/	/
	PE	/	/	/	/	/	/	/	/
	L1+L2	/	/	A	A	/	/	/	/
	L1 + PE	/	/	/	/	/	/	/	/
	L2 + PE	/	/	/	/	/	/	/	/
	L1+L2+PE	/	/	/	/	/	/	/	/
Signal ports	RJ45	/	/	/	/	/	/	/	/

Test Result: Pass

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8. Surges

8.1 Test Procedure

Test is conducting under the description of EN 61000-4-5.

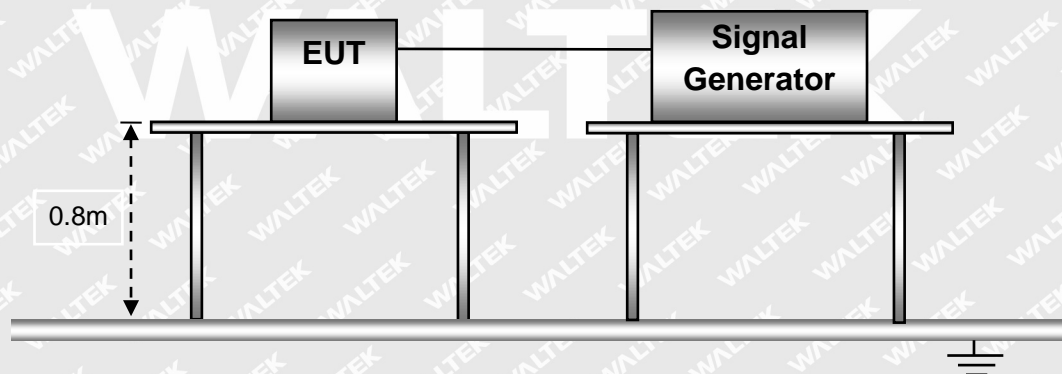
8.2 Test Performance

Performance Criterion: B

8.3 Environmental Conditions

Temperature:	25 °C
Relative Humidity:	53%
ATM Pressure:	1011 mbar

8.4 Basic Test Setup Block Diagram



**8.5 Surge Test Data**

Test Voltage (kV)	Poll	Path	Pass	Fail
0.5kV	±	L-N	/	/
1kV	±	L-N	A	/
2kV	±	L-PE, N-PE	/	/
4kV	±	L-N, L-PE, N-PE	/	/

Test Result: Pass

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9. Continuous induced RF disturbances (C/S)

9.1 Test Procedure

Test is conducting under the description of EN 61000-4-6.

9.2 Test Performance

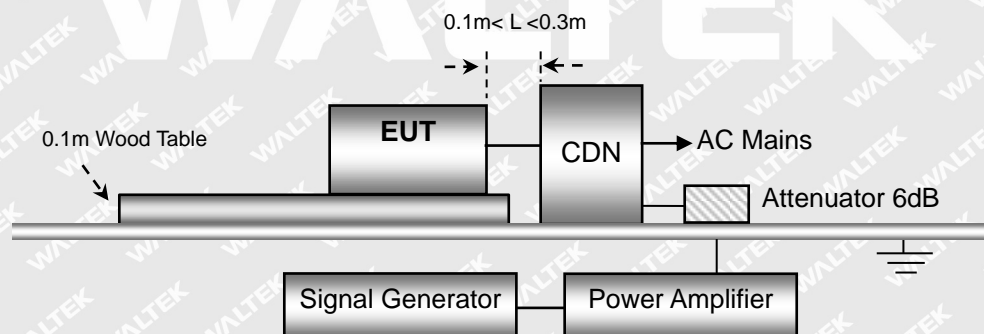
Performance Criterion: A

9.3 Environmental Conditions

Temperature:	25 °C
Relative Humidity:	53%
ATM Pressure:	1011 mbar

9.4 Basic Test Setup Block Diagram

For AC Mains or DC Input:





9.5 Continuous Conducted Disturbances Test Data

Sweep frequency range: 0.15 MHz to 10 MHz 3 V; 10 MHz to 30 MHz 3 V to 1 V; 30 MHz to 80 MHz 1V

Frequency step: 1% of fundamental

Dwell time: 1 second

AC Port

Frequency MHz	Injected Position	Voltage level (e.m.f.)	Observations (Performance Criterion)	Result
0.15-10	AC Mains	3V	A	Pass
10-30	AC Mains	3-1V	A	Pass
30-80	AC Mains	1V	A	Pass

Test Result: Pass

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10. Power-Frequency Magnetic Fields (PFMF)

10.1 Test Procedure

Test is conducting under the description of EN 61000-4-8.

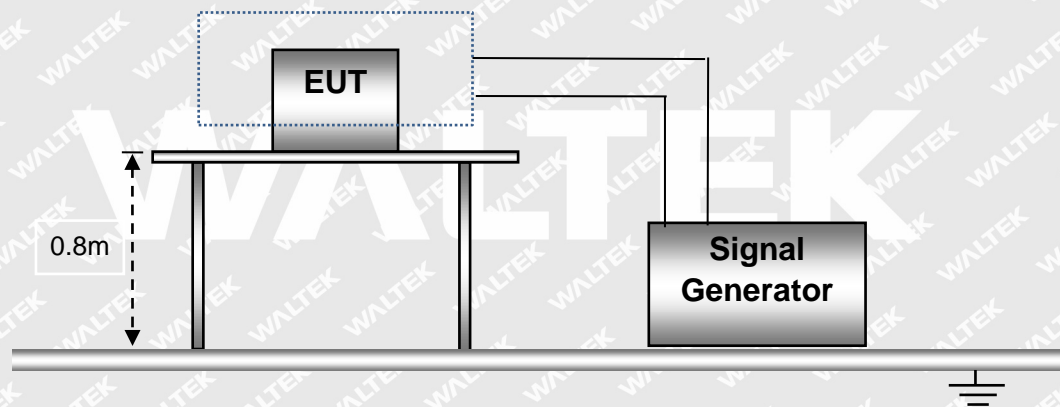
10.2 Test Performance

Performance Criterion: A

10.3 Environmental Conditions

Temperature:	25 °C
Relative Humidity:	50%
ATM Pressure:	1011 mbar

10.4 Basic Test Setup Block Diagram



**10.5 Power-Frequency Magnetic Field Test Data**

Level	Magnetic Field Strength (r.m.s) A/m	Frequency Hz	Induction Coil Position	Pass	Fail
1	1	50	X, Y, Z	A	/
2	3	50	X, Y, Z	/	/
3	10	50	X, Y, Z	/	/
X	Special	/	/	/	/

Test Result: Pass

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EXHIBIT 1 - PRODUCT LABELING

Proposed CE Label Format

Gaming Mouse

Model: GM200*****(*=A~Z,a~z,0~9,/,or blank),JGH

Brand: /

Importer Name: XXX

Importer Address: XXX

TPV Electronics (Fujian) Co, Ltd.

Rongqiao Economic and Technological Development
Zone, Fuqing City, Fujian Province, P.R.China



Specifications: Text is Black in color and is justified. Labels are printed in indelible ink on permanent adhesive backing or silk-screened onto the EUT or shall be affixed at a conspicuous location on the EUT. The 'CE' marking must be affixed to the EUT or to its data plate. Where this is not possible or not warranted on account of the nature of the apparatus, it must be affixed to the packaging, if any, and to the accompanying documents. The 'CE' marking is allowed less than 5 mm but must clear. If the 'CE' marking is reduced or enlarged the proportions given in the above graduated drawing must be respected. The Importer name, address and Manufacturer name and address should indicate on marking label or packaging or in a document accompanying

Proposed Label Location on EUT

CE Label Location





EXHIBIT 2 - EUT PHOTOGRAPHS

EUT View 1



EUT View 2





EUT View 3



EUT View 4





EUT View 5

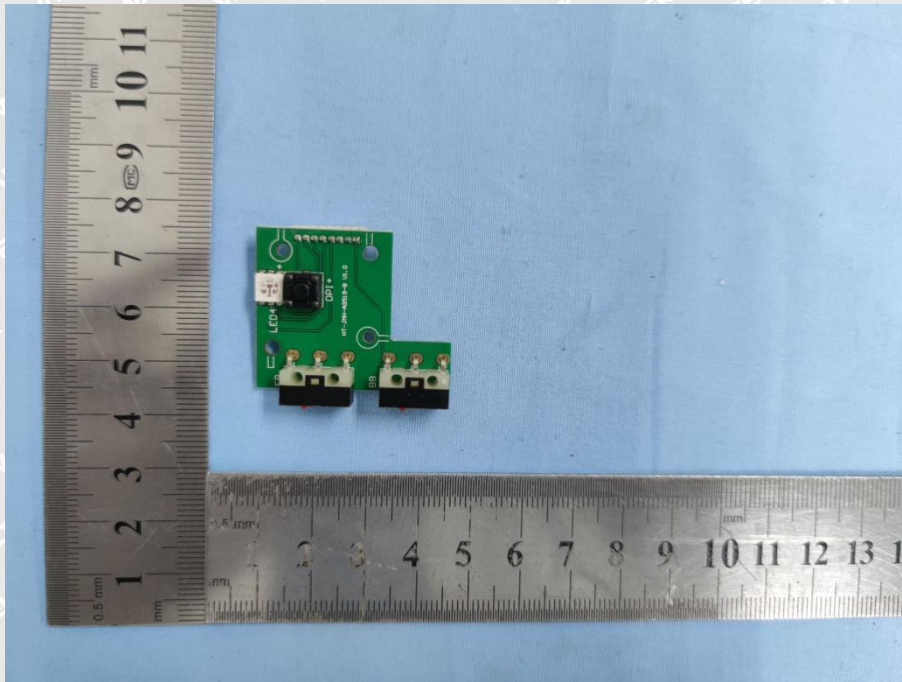


EUT View 6

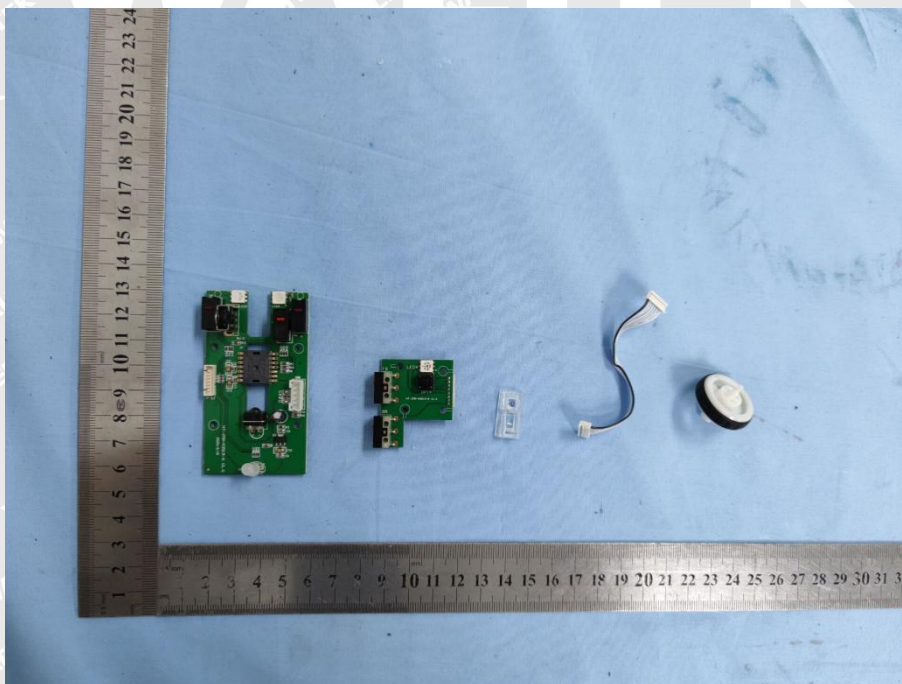




EUT Housing and Board View 1

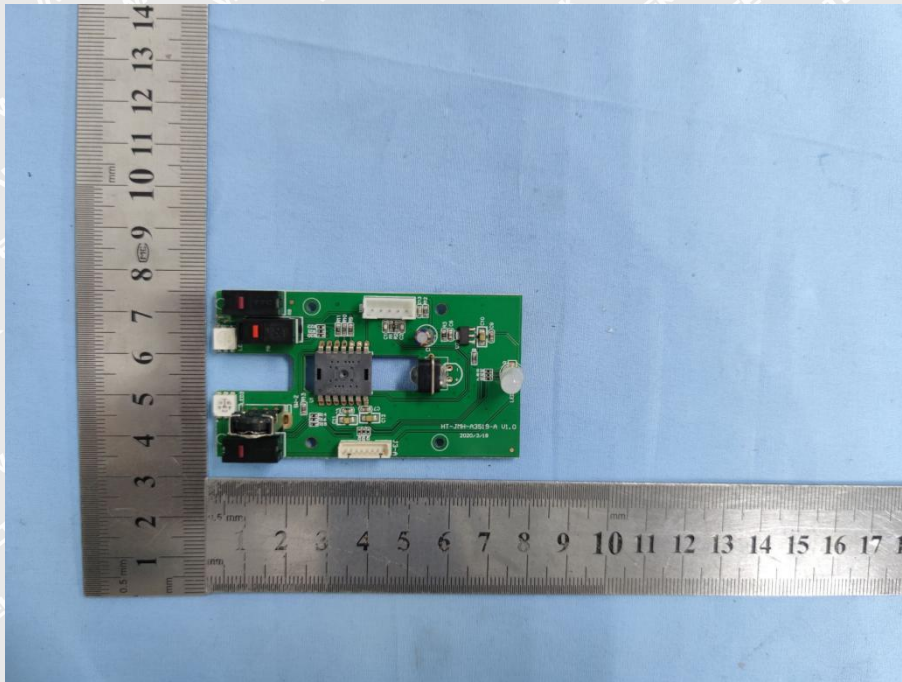


Solder Board-Component View 2

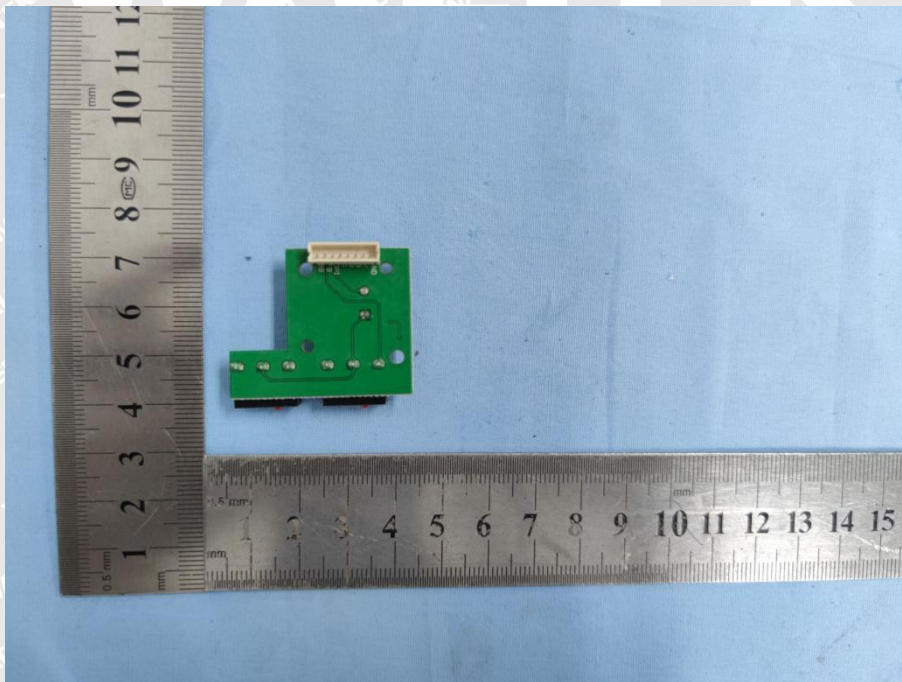




Solder Board-Component View 3

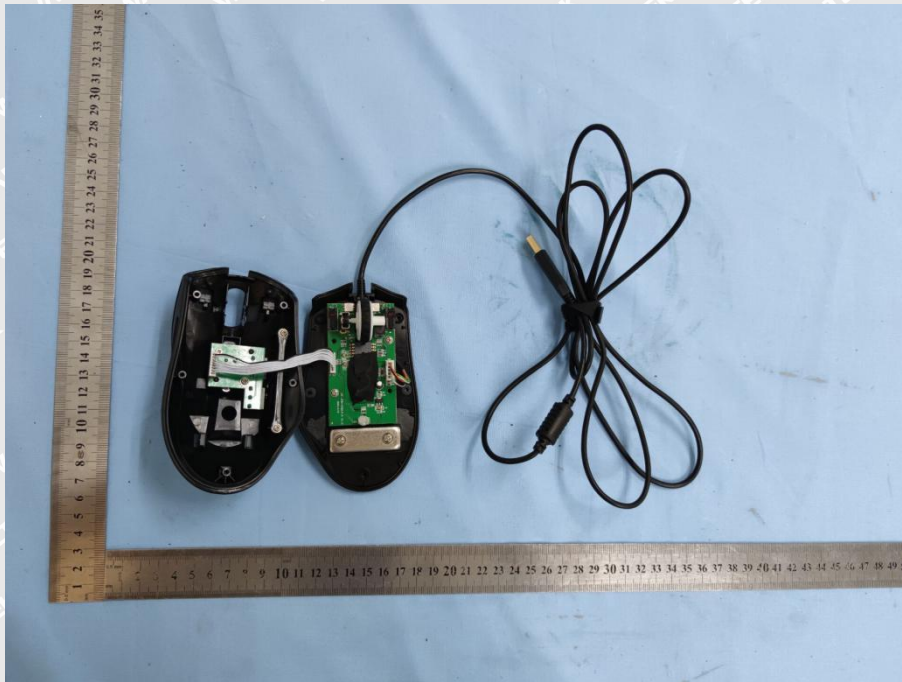


Solder Board-Component View 4





Solder Board-Component View 5



Solder Board-Component View 6

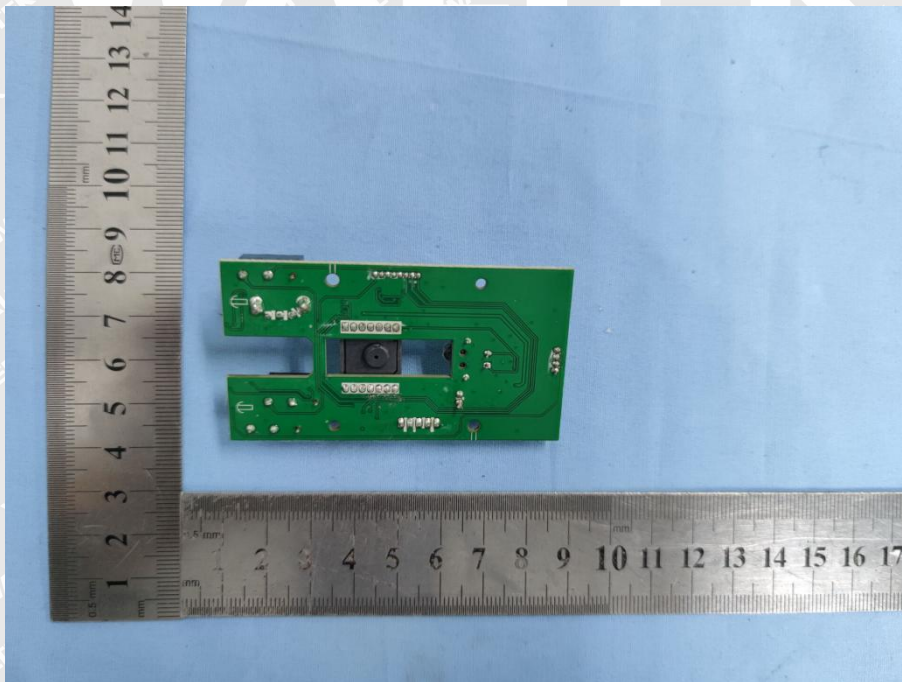


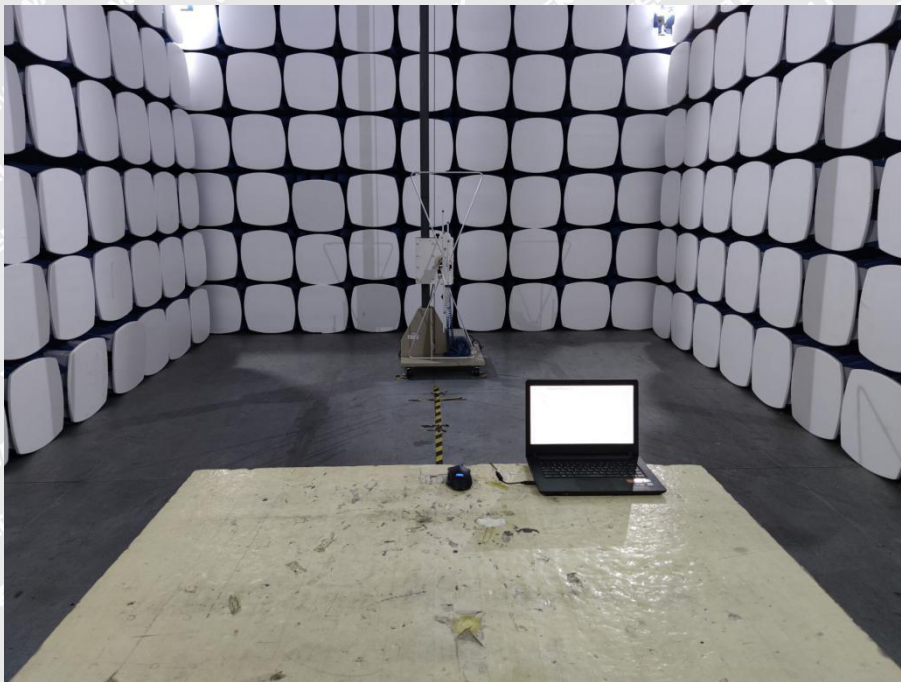


EXHIBIT 3 - TEST SETUP PHOTOGRAPHS

Conduction Emission Test View



Radiation Emission Test View

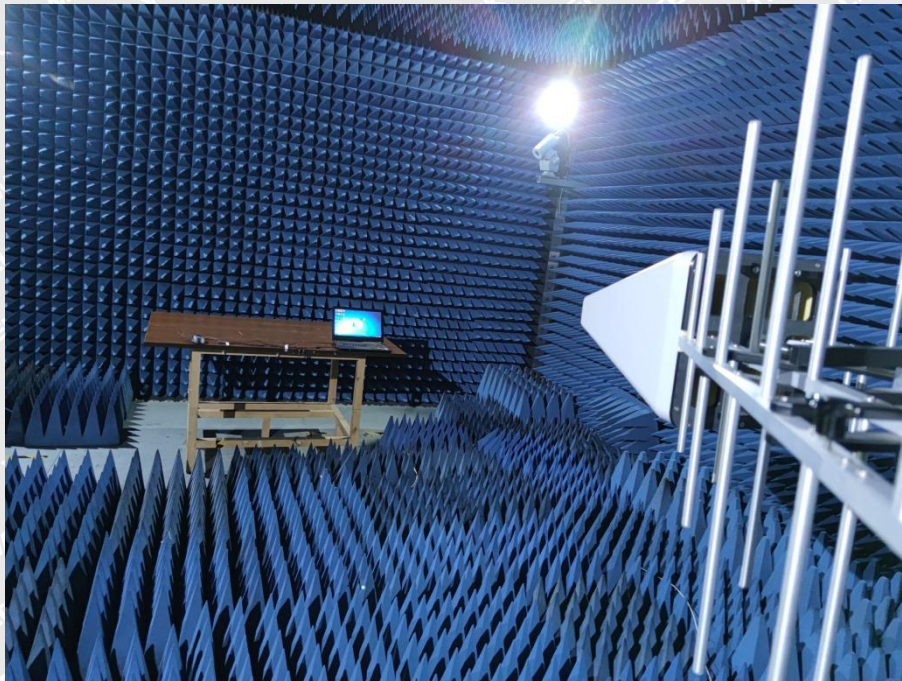




EN 61000-4-2 Test View



EN 61000-4-3 Test View



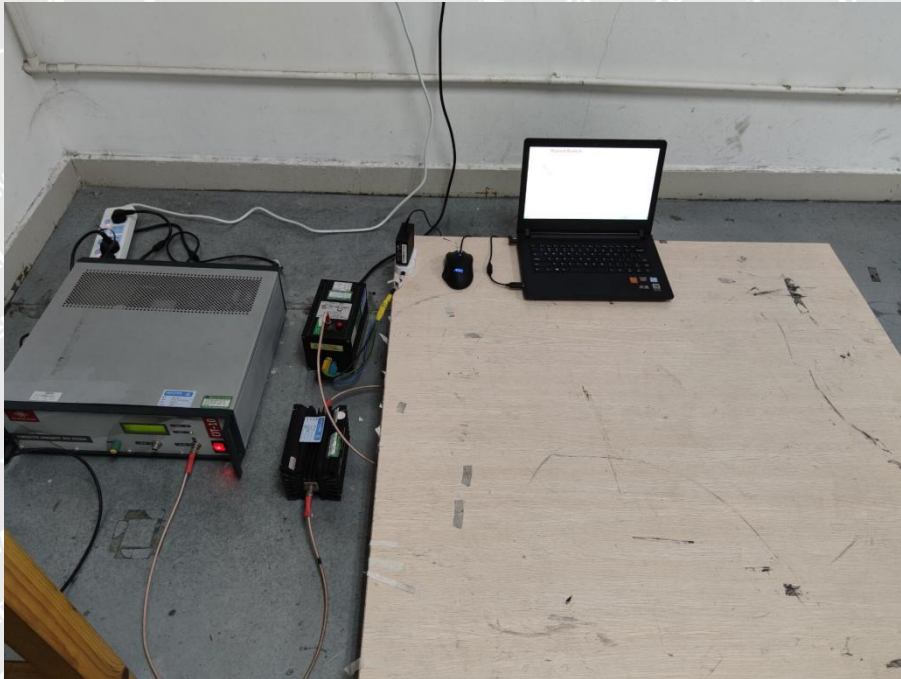


EN 61000-4-4/5/11 Test View



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EN 61000-4-6 Test View





EN 61000-4-8 Test View



******* END OF REPORT *******

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